**Product data sheet** 

### 1. General description

Planar passivated high commutation three quadrant triac in a SOT404 (D2PAK) surface mountable plastic package. This "series ET" triac balances the requirements of commutation performance and gate sensitivity and is intended for interfacing with low power drivers including microcontrollers. It is used in applications where "high junction operating temperature" capability is required.

#### 2. Features and benefits

- · 3Q technology for improved noise immunity
- Direct interfacing with low power drivers and microcontrollers
- · Good immunity to false turn-on by dV/dt
- · High commutation capability with sensitive gate
- High junction operating temperature capability
- · High voltage capability
- Planar passivated for voltage ruggedness and reliability
- · Sensitive gate for easy logic level triggering
- Surface mountable package
- Triggering in three quadrants only

## 3. Applications

- · Applications subject to high temperature
- Electronic thermostats (heating and cooling)
- · High power motor controls e.g. washing machines and vacuum cleaners
- · Refrigeration and air-conditioner compressor controls

#### 4. Quick reference data

Table 1. Quick reference data

| Symbol              | Parameter                                | Conditions   |   | Min | Тур | Max | Unit |
|---------------------|--|--|---|-----|-----|-----|------|
| $V_{DRM}$           | repetitive peak off-<br>state voltage    |  | - | •   | -   | 800 | V    |
| I <sub>T(RMS)</sub> | RMS on-state current                     | full sine wave; $T_{mb} \le 125 ^{\circ}\text{C}$ ; Fig. 1; Fig. 2; Fig. 3   | - | •   | -   | 12  | Α    |
| I <sub>TSM</sub>    | non-repetitive peak on-<br>state current | full sine wave; $T_{j(init)} = 25 ^{\circ}\text{C}$ ;<br>$t_p = 20  \text{ms}$ ; $\underline{\text{Fig. 4}}$ ; $\underline{\text{Fig. 5}}$ | - | •   | -   | 100 | Α    |
|                     |  | full sine wave; $T_{j(init)} = 25 ^{\circ}C$ ;<br>$t_p = 16.7  \text{ms}$  | - | •   | -   | 110 | Α    |
| Tį                  | junction temperature                     |  | - |     | -   | 150 | °C   |

| Symbol                | Parameter                             | Conditions  | Min | Тур | Max | Unit |
|-----------------------|---------------------------------------|---|-----|-----|-----|------|
| I <sub>GT</sub>       | gate trigger current                  | $V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2+ \text{ G+;} $ $T_j = 25 \text{ °C; } \frac{\text{Fig. 7}}{}$                      | -   | -   | 10  | mA   |
|                       |                                       | $V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G-;$<br>$T_j = 25 \text{ °C; } \frac{\text{Fig. 7}}{}$                           | -   | -   | 10  | mA   |
|                       |                                       | $V_D = 12 \text{ V; } I_T = 0.1 \text{ A; T2- G-;}$<br>$T_j = 25 \text{ °C; } \frac{\text{Fig. 7}}{}$                             | -   | -   | 10  | mA   |
| I <sub>H</sub>        | holding current                       | V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 9</u>  | -   | -   | 15  | mA   |
| $V_{T}$               | on-state voltage                      | I <sub>T</sub> = 15 A; T <sub>j</sub> = 25 °C; <u>Fig. 10</u>   | -   | 1.3 | 1.6 | V    |
| Dynamic ch            | naracteristics                        |   |     |     |     | _    |
| dV <sub>D</sub> /dt   | rate of rise of off-state voltage     | $V_{DM}$ = 536 V; $T_j$ = 150 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit                        | 30  | -   | -   | V/µs |
| dl <sub>com</sub> /dt | rate of change of commutating current | $V_D$ = 400 V; $T_j$ = 150 °C; $I_{T(RMS)}$ = 12 A; $dV_{com}/dt$ = 20 V/ $\mu$ s; (without snubber condition); gate open circuit | 2   | -   | -   | A/ms |
|                       |                                       | $V_D$ = 400 V; $T_j$ = 150 °C; $I_{T(RMS)}$ = 12 A; $dV_{com}/dt$ = 10 V/ $\mu$ s; gate open circuit                              | 3.5 | -   | -   | A/ms |
|                       |                                       | $V_D$ = 400 V; $T_j$ = 150 °C; $I_{T(RMS)}$ = 12 A; $dV_{com}/dt$ = 1 V/µs; gate open circuit                                     | 5   | -   | -   | A/ms |

# 5. Pinning information

**Table 2. Pinning information** 

| Pin | Symbol | Description                    | Simplified outline | Graphic symbol |
|-----|--------|--------------------------------|--------------------|----------------|
| 1   | T1     | main terminal 1                | mb                 | T2             |
| 2   | T2     | main terminal 2                |                    | G<br>sym051    |
| 3   | G      | gate                           | Ī                  | Sylliosi       |
| mb  | T2     | mounting base; main terminal 2 |                    |                |
|     |        |                                | D2PAK (SOT404)     |                |

# 6. Ordering information

**Table 3. Ordering information** 

| Type number   | Package |  |         |  |  |
|---------------|---------|--|---------|--|--|
|               | Name    | Description  | Version |  |  |
| BTA312B-800ET | D2PAK   | plastic single-ended surface-mounted package (D2PAK); 3 leads (one lead cropped) | SOT404  |  |  |

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# 7. Limiting values

### **Table 4. Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol              | Parameter                                | Conditions   | Min | Max | Unit |
|---------------------|--|--|-----|-----|------|
| $V_{DRM}$           | repetitive peak off-state voltage        |  | -   | 800 | V    |
| I <sub>T(RMS)</sub> | RMS on-state current                     | full sine wave; $T_{mb} \le 125 ^{\circ}\text{C}$ ; Fig. 1; Fig. 2; Fig. 3 | -   | 12  | A    |
| I <sub>TSM</sub>    | non-repetitive peak on-<br>state current | full sine wave; $T_{j(init)}$ = 25 °C; $t_p$ = 20 ms;<br>Fig. 4; Fig. 5    | -   | 100 | Α    |
|                     |  | full sine wave; $T_{j(init)} = 25 ^{\circ}C$ ; $t_p = 16.7  \text{ms}$     | -   | 110 | Α    |
| l <sup>2</sup> t    | I <sup>2</sup> t for fusing              | t <sub>p</sub> = 10 ms; SIN  | -   | 50  | A²s  |
| dl <sub>T</sub> /dt | rate of rise of on-state current         | I <sub>G</sub> = 20 mA   | -   | 100 | A/µs |
| I <sub>GM</sub>     | peak gate current                        |  | -   | 2   | Α    |
| $P_{GM}$            | peak gate power                          |  | -   | 5   | W    |
| P <sub>G(AV)</sub>  | average gate power                       | over any 20 ms period  | -   | 0.5 | W    |
| T <sub>stg</sub>    | storage temperature                      |  | -40 | 150 | °C   |
| T <sub>j</sub>      | junction temperature                     |  | -   | 150 | °C   |

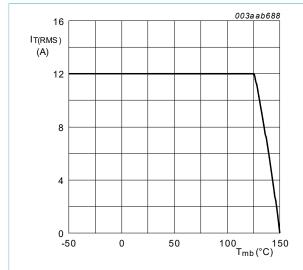
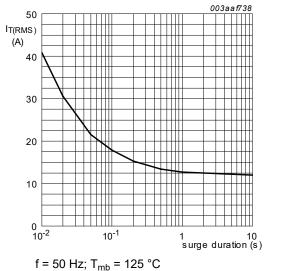


Fig. 1. RMS on-state current as a function of mounting base temperature; maximum values



1 – 30 Hz, 1<sub>mb</sub> – 123 C

Fig. 2. RMS on-state current as a function of surge duration; maximum values

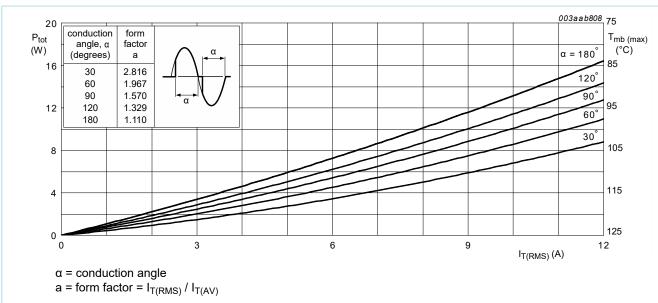


Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values

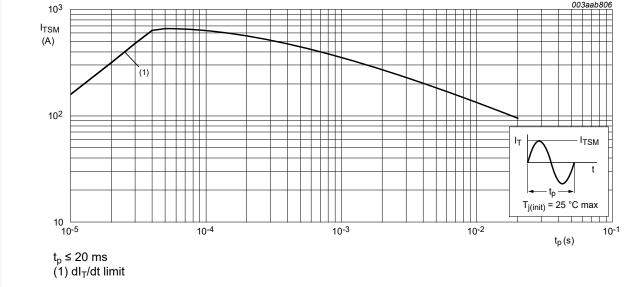


Fig. 4. Non-repetitive peak on-state current as a function of pulse duration; maximum values

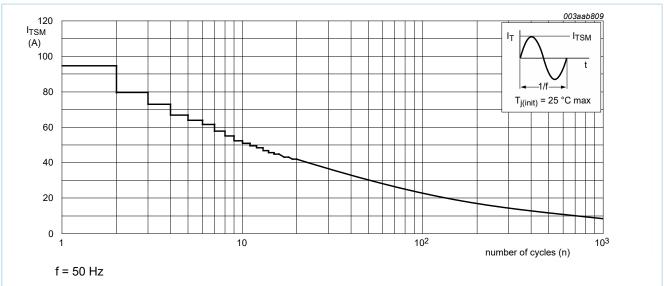
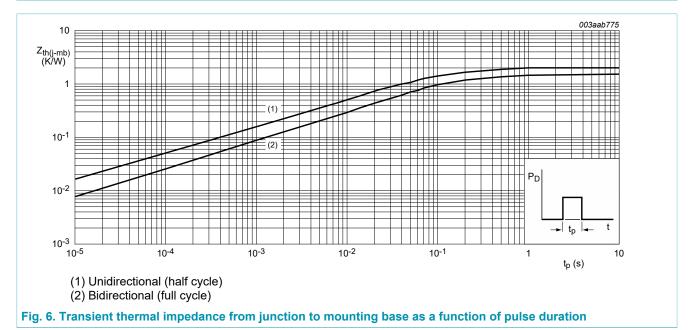


Fig. 5. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values

#### 8. Thermal characteristics

**Table 5. Thermal characteristics** 

| Symbol                | Parameter  | Conditions                                       | Min | Тур | Max | Unit |
|-----------------------|--|--|-----|-----|-----|------|
| R <sub>th(j-mb)</sub> | thermal resistance<br>from junction to<br>mounting base    | full cycle; Fig. 6                               | -   | -   | 1.5 | K/W  |
|                       |  | half cycle; Fig. 6                               | -   | -   | 2   | K/W  |
| $R_{th(j-a)}$         | thermal resistance<br>from junction to<br>ambient free air | printed circuit board mounted; minimum footprint | -   | 55  | -   | K/W  |



## 9. Characteristics

#### **Table 6. Characteristics**

| Symbol                | Parameter                             | Conditions  | Min  | Тур | Max | Unit |
|-----------------------|---------------------------------------|---|------|-----|-----|------|
| Static char           | acteristics                           |   |      |     | ,   |      |
| I <sub>GT</sub>       | gate trigger current                  | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ G+;$<br>$T_j = 25 \text{ °C}; Fig. 7$   | -    | -   | 10  | mA   |
|                       |                                       | $V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G-;$<br>$T_j = 25 \text{ °C; } Fig. 7$                                     | -    | -   | 10  | mA   |
|                       |                                       | $V_D = 12 \text{ V; } I_T = 0.1 \text{ A; T2- G-;}$<br>$T_j = 25 \text{ °C; } Fig. 7$                                       | -    | -   | 10  | mA   |
| IL                    | latching current                      | $V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T2+ G+;$<br>$T_j = 25 \text{ °C}; Fig. 8$   | -    | -   | 25  | mA   |
|                       |                                       | $V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T2+ G-;$<br>$T_j = 25 \text{ °C}; Fig. 8$   | -    | -   | 30  | mA   |
|                       |                                       | $V_D = 12 \text{ V; } I_G = 0.1 \text{ A; T2- G-;}$<br>$T_j = 25 \text{ °C; } Fig. 8$                                       | -    | -   | 25  | mA   |
| I <sub>H</sub>        | holding current                       | V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 9</u>  | -    | -   | 15  | mA   |
| V <sub>T</sub>        | on-state voltage                      | I <sub>T</sub> = 15 A; T <sub>j</sub> = 25 °C; <u>Fig. 10</u>   | -    | 1.3 | 1.6 | V    |
| V <sub>GT</sub>       | gate trigger voltage                  | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 \text{ °C};$<br>Fig. 11  | -    | 0.7 | 1   | V    |
|                       |                                       | $V_D = 400 \text{ V}; I_T = 0.1 \text{ A}; T_j = 150 ^{\circ}\text{C};$<br>Fig. 11  | 0.25 | 0.4 | -   | V    |
| I <sub>D</sub>        | off-state current                     | V <sub>D</sub> = 800 V; T <sub>j</sub> = 150 °C   | -    | 0.4 | 2   | mA   |
| Dynamic cl            | haracteristics                        |   | ·    |     |     |      |
| dV <sub>D</sub> /dt   | rate of rise of off-state voltage     | $V_{DM}$ = 536 V; $T_j$ = 150 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit                  | 30   | -   | -   | V/µs |
| dl <sub>com</sub> /dt | rate of change of commutating current | $V_D$ = 400 V; $T_j$ = 150 °C; $I_{T(RMS)}$ = 12 A; $dV_{com}/dt$ = 20 V/µs; (without snubber condition); gate open circuit | 2    | -   | -   | A/ms |
|                       |                                       | $V_D$ = 400 V; $T_j$ = 150 °C; $I_{T(RMS)}$ = 12 A; $dV_{com}/dt$ = 10 V/µs; gate open circuit                              | 3.5  | -   | -   | A/ms |
|                       |                                       | $V_D$ = 400 V; $T_j$ = 150 °C; $I_{T(RMS)}$ = 12 A; $dV_{com}/dt$ = 1 V/µs; gate open circuit                               | 5    | -   | -   | A/ms |

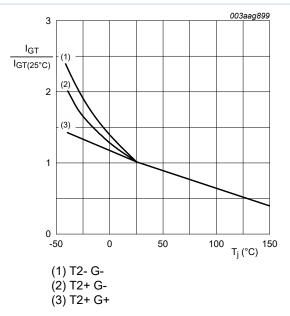


Fig. 7. Normalized gate trigger current as a function of junction temperature

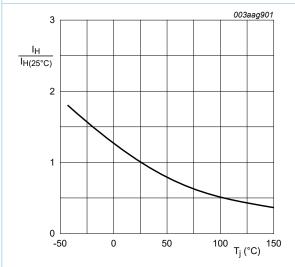


Fig. 9. Normalized holding current as a function of junction temperature

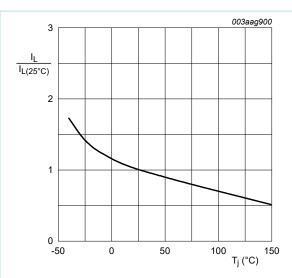
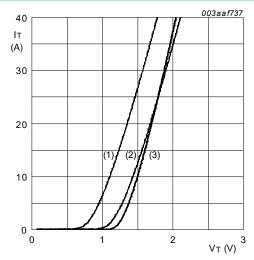


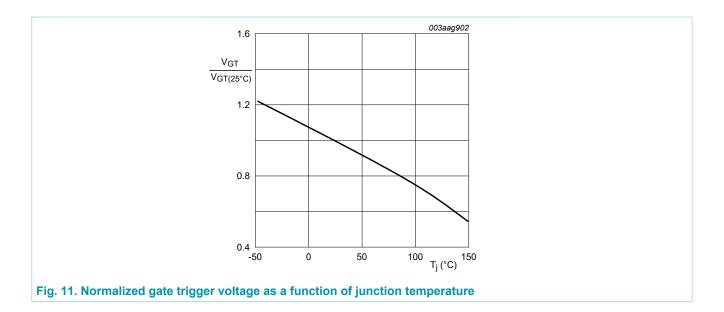
Fig. 8. Normalized latching current as a function of junction temperature



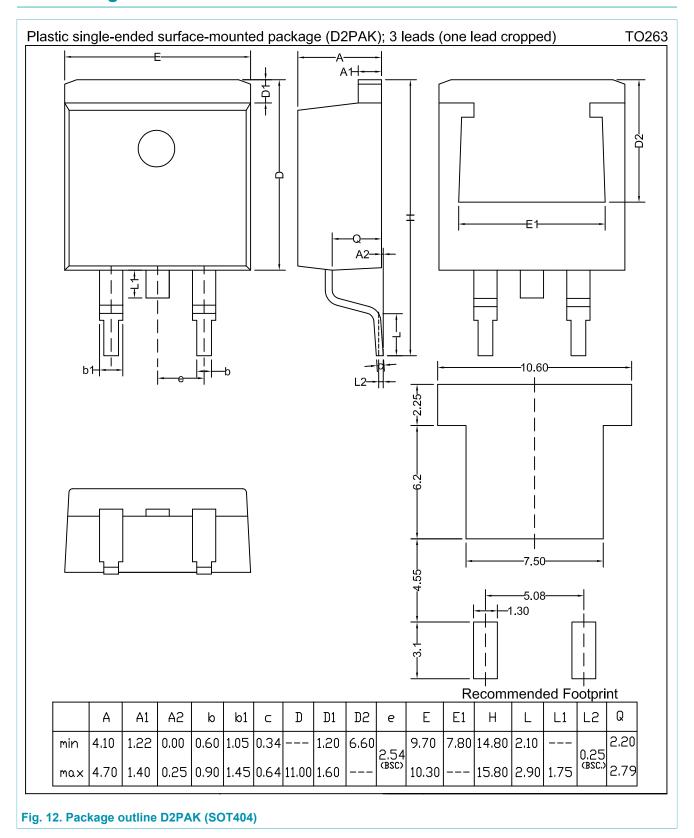
 $V_o$  = 1.127 V;  $R_s$  = 0.27  $\Omega$ 

(1)  $T_j = 150$  °C; typical values (2)  $T_j = 150$  °C; maximum values (3)  $T_j = 25$  °C; maximum values

Fig. 10. On-state current as a function of on-state voltage



## 10. Package outline



### 11. Legal information

#### **Data sheet status**

| Document status [1][2]               | Product status [3] | Definition  |
|--------------------------------------|--------------------|---|
| Objective<br>[short] data<br>sheet   | Development        | This document contains data from the objective specification for product development. |
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For more information, please visit: http://www.ween-semi.com
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